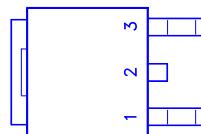
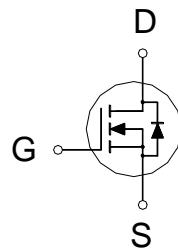


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
**P0770JD
TO-252**

Halogen-Free & Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
700V	653mΩ	7A



1. GATE
-
2. DRAIN
-
3. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	700	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current ²	I_D	7	A
$T_C = 100^\circ C$	I_D	4.3	
Pulsed Drain Current ¹	I_{DM}	21	
Avalanche Current ³	I_{AS}	1.2	
Avalanche Energy ³	E_{AS}	54	mJ
Power Dissipation	P_D	71	W
$T_C = 100^\circ C$	P_D	29	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		1.75	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.²Ensure that the channel temperature does not exceed 150°C.³ $V_{DD} = 50V$, $L = 75mH$, starting $T_J = 25^\circ C$.

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ELECTRICAL CHARACTERISTICS (T_J = 25 ° C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = 250μA	700			V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	2	3.3	4	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0V, V _{GS} = ±30V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 700V, V _{GS} = 0V			1	
		V _{DS} = 560V, V _{GS} = 0V, T _J = 100 ° C			10	μA
Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = 10V, I _D = 3.5A		540	653	mΩ
Forward Transconductance ¹	g _{fs}	V _{DS} = 15V, I _D = 3.5A		6.3		S
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = 100V, f = 250KHz		538		pF
Output Capacitance	C _{oss}			29		
Reverse Transfer Capacitance	C _{rss}			4.6		
Gate Resistance	R _g	V _{GS} = 0V, V _{DS} = 0V, f = 1MHz		20		Ω
Total Gate Charge ²	Q _g	V _{DS} = 560V, V _{GS} = 10V, I _D = 3.5A		19		nC
Gate-Source Charge ²	Q _{gs}			3.6		
Gate-Drain Charge ²	Q _{gd}			8.8		
Turn-On Delay Time ²	t _{d(on)}	V _{DD} = 350V, I _D ≈ 3.5A, V _{GS} = 10V, R _{GEN} = 25Ω		21		nS
Rise Time ²	t _r			36		
Turn-Off Delay Time ²	t _{d(off)}			102		
Fall Time ²	t _f			58		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_J = 25 ° C)						
Continuous Current	I _S				7	A
Forward Voltage ¹	V _{SD}	I _F = 7A , V _{GS} = 0V			1.2	V
Reverse Recovery Time	t _{rr}	I _F = 3.5A , dI _F /dt= 100A/μs		235		nS
Reverse Recovery Charge	Q _{rr}			2		uC

¹Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.²Independent of operating temperature.

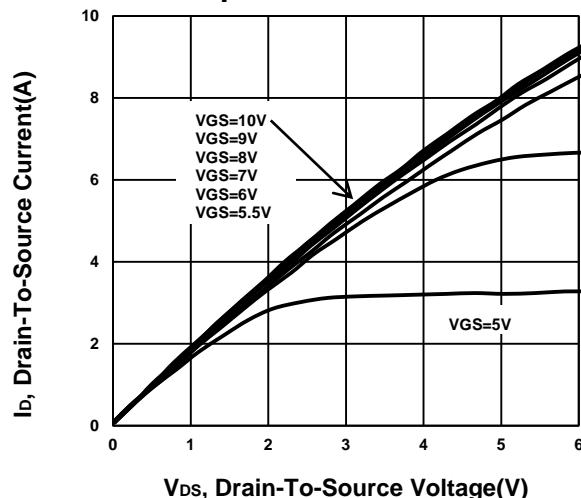
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**N-Channel Enhancement Mode
Field Effect Transistor**

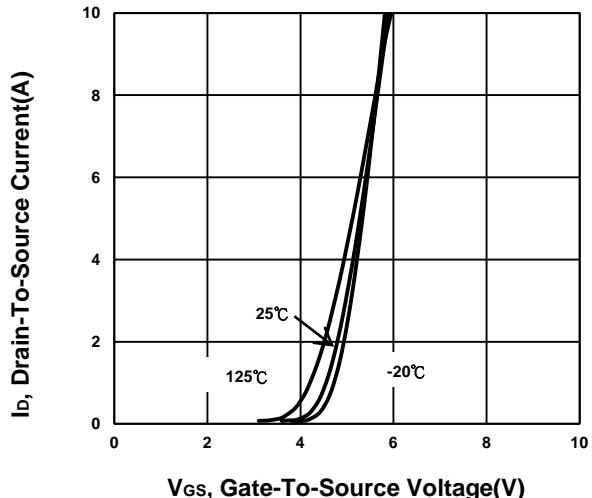
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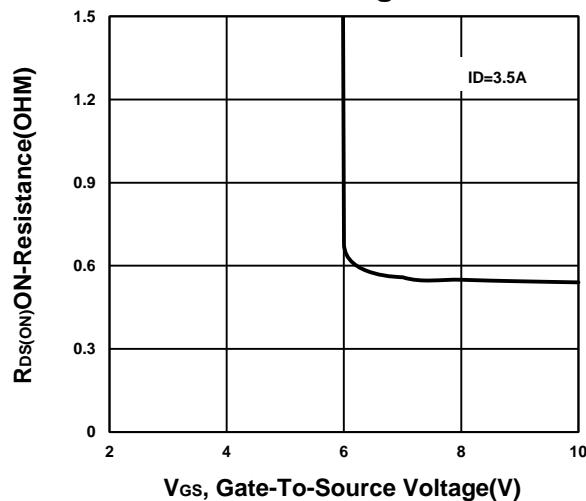
Output Characteristics



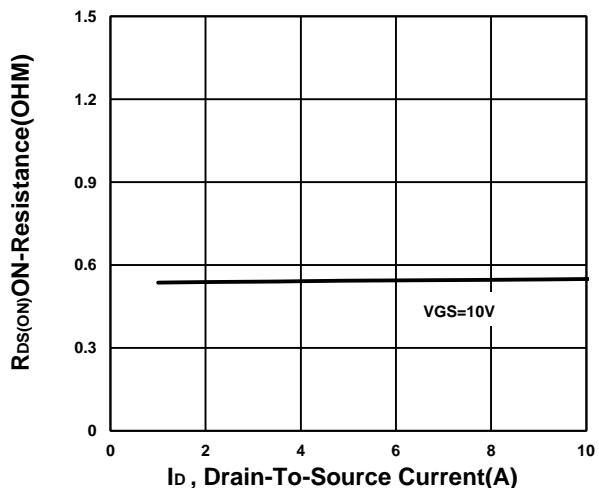
Transfer Characteristics



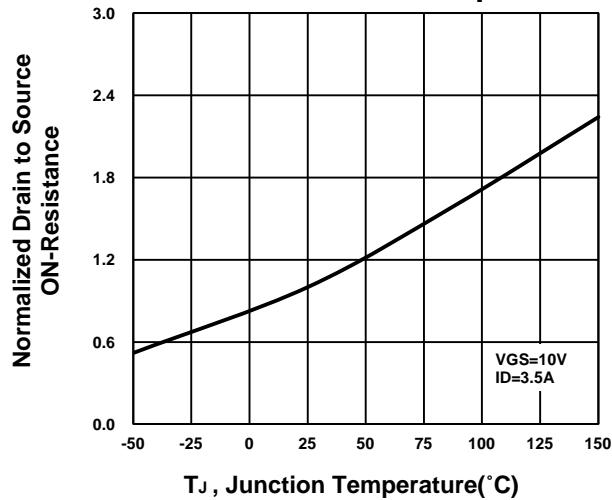
On-Resistance VS Gate-To-Source Voltage



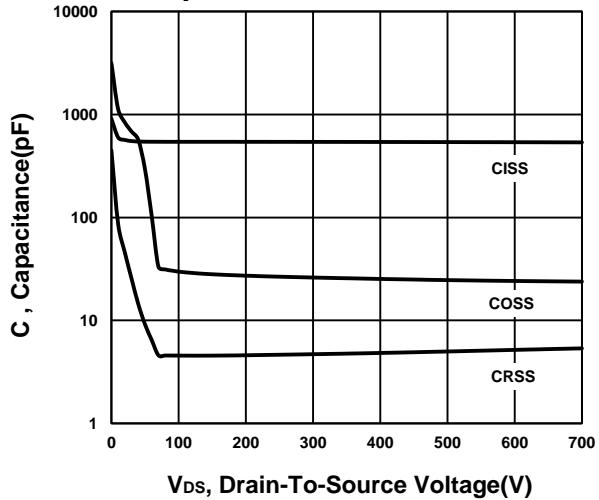
On-Resistance VS Drain Current



On-Resistance VS Temperature



Capacitance Characteristic



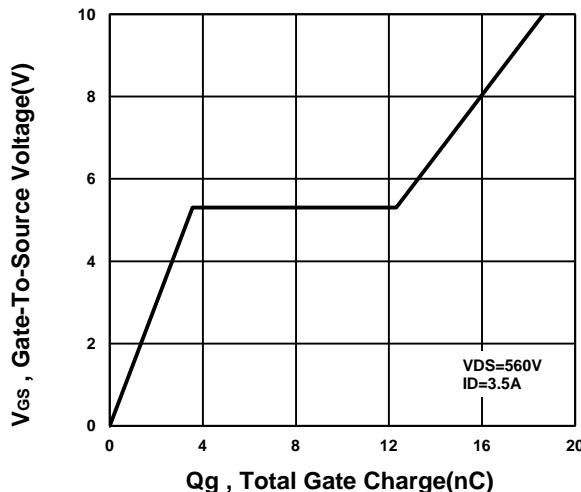
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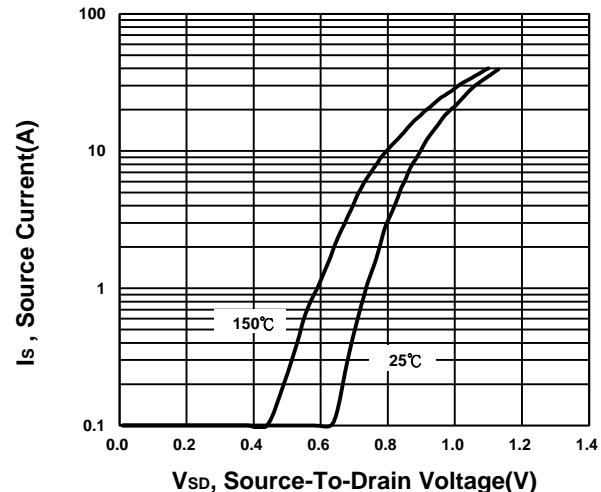
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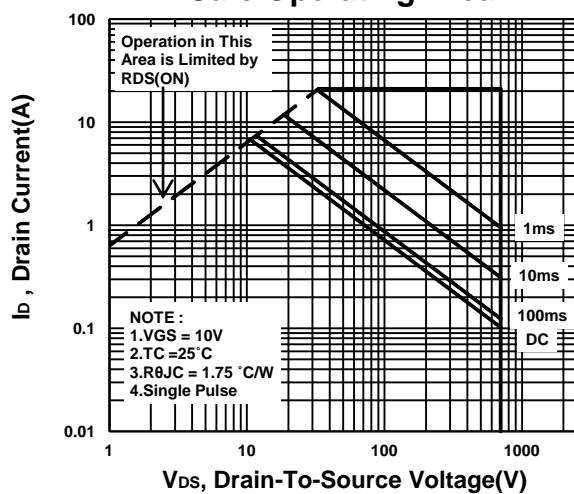
Gate charge Characteristics



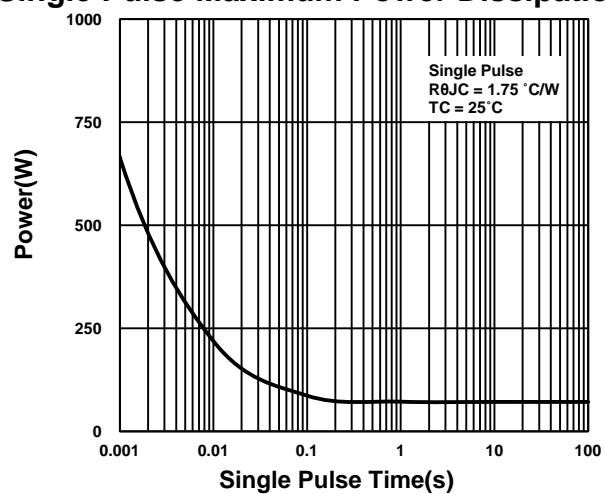
Source-Drain Diode Forward Voltage



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

